

## FAST GATE TURN-OFF THYRISTORS

Thyristors in SOT-93 envelopes which are capable of being turned both on and off via the gate, and may be used with gate-assisted turn-off in anode-commutated circuits. They are suitable for use in resonant power supplies, high-frequency inverters, motor control etc. The devices have no reverse blocking capability; for reverse blocking operation use with a series diode, for reverse conducting operation use with an anti-parallel diode. The anode is connected to the mounting base.

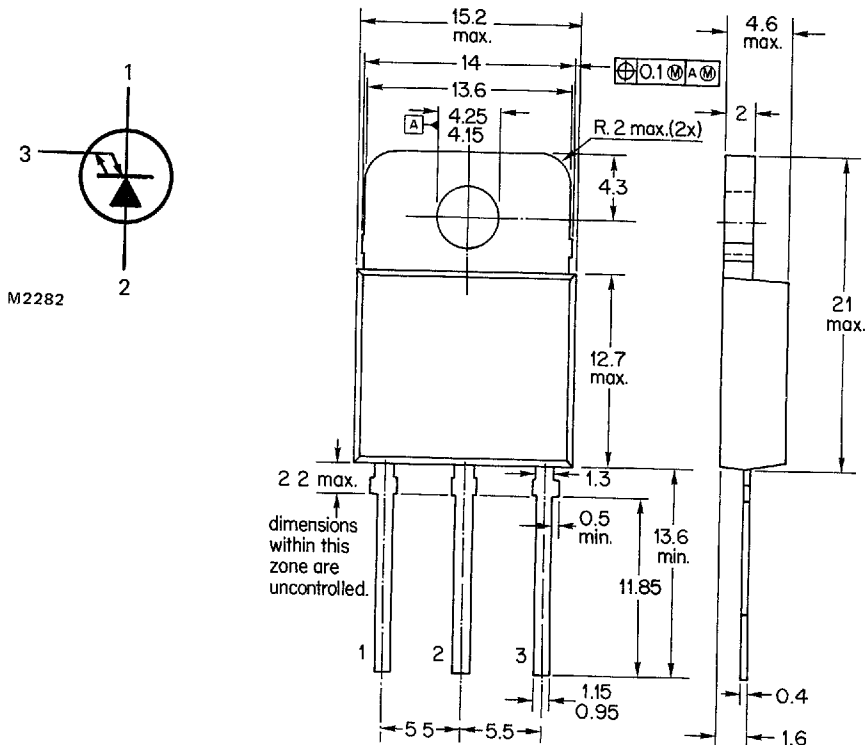
### QUICK REFERENCE DATA

		BTR59-800R		1300R	
Repetitive peak off-state voltage	$V_{DRM}$	max.	800	1300	V
Controllable anode current	$I_{TCRM}$	max.	50		A
Average on-state current	$I_T(AV)$	max.	10		A
Circuit commutated turn-off time	$t_q$	<	1.0		$\mu s$

### MECHANICAL DATA

Dimensions in mm

Fig.1 SOT93; anode connected to mounting base.



Accessories supplied on request; see data sheets Mounting instructions and accessories for SOT-93 envelopes.

**RATINGS**

Limiting values in accordance with the Absolute Maximum System (IEC134).

		BTR59-800R	1300R	
<b>Anode to cathode</b>				
Transient off-state voltage	$V_{DSM}$	max. 800	1300	V*
Repetitive peak off-state voltage	$V_{DRM}$	max. 800	1300	V*
Working off-state voltage	$V_{DW}$	max. 600	1000	V*
Continuous off-state voltage	$V_D$	max. 400	750	V*
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 85\text{ }^\circ\text{C}$	$I_T(AV)$	max.	10	A
R.M.S. on-state current	$I_T(RMS)$	max.	16.5	A
Controllable anode current	$I_{TCRM}$	max.	50	A
Non-repetitive peak on-state current t = 10 ms; half-sinewave; $T_j = 120\text{ }^\circ\text{C}$ prior to surge	$I_{TSM}$	max.	100	A
$I^2t$ for fusing; t = 10 ms	$I^2t$	max.	50	A <sup>2</sup> s
Total power dissipation up to $T_{mb} = 25\text{ }^\circ\text{C}$	$P_{tot}$	max.	105	W
<b>Gate to cathode</b>				
Repetitive peak current $T_j = 120\text{ }^\circ\text{C}$ prior to surge gate-cathode forward; t = 10 ms; half-sinewave	$I_{GFM}$	max.	25	A
gate-cathode reverse; t = 20 $\mu$ s	$I_{GRM}$	max.	25	A
Average power dissipation (averaged over any 20 ms period)	$P_G(AV)$	max.	5.0	W
<b>Temperatures</b>				
Storage temperature	$T_{stg}$		-40 to +125	$^\circ\text{C}$
Operating junction temperature	$T_j$	max.	120	$^\circ\text{C}$
<b>THERMAL RESISTANCE</b>				
From mounting base to heatsink; with heatsink compound	$R_{th\ mb-h}$	=	0.2	K/W
From junction to mounting base	$R_{th\ j-mb}$	=	0.9	K/W

\*Measured with gate-cathode connected together.

**CHARACTERISTICS**

**Anode to cathode**

On-state voltage

$I_T = 10 \text{ A}; I_G = 0.5 \text{ A}; T_j = 120 \text{ }^\circ\text{C}$   $V_T < 3.0 \text{ V}^*$

Rate of rise of off-state voltage that will not trigger any off-state device; exponential method

$V_D = 2/3 V_{Dmax}; V_{GR} = 5 \text{ V}; T_j = 120 \text{ }^\circ\text{C}$   $dV_D/dt < 10 \text{ kV}/\mu\text{s}$

Rate of rise of off-state voltage that will not trigger any device following conduction, linear method

$I_T = 20 \text{ A}; V_D = V_{DRMmax}; V_{GR} = 10 \text{ V}; T_j = 120 \text{ }^\circ\text{C}$   $dV_D/dt < 1.0 \text{ kV}/\mu\text{s}$

Off-state current

$V_D = V_{Dmax}; T_j = 120 \text{ }^\circ\text{C}$   $I_D < 5.0 \text{ mA}$

Latching current;  $T_j = 25 \text{ }^\circ\text{C}$

$I_L \text{ typ. } 1.5 \text{ A}^{**}$

**Gate to cathode**

Voltage that will trigger all devices

$V_D = 12 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$   $V_{GT} > 1.5 \text{ V}$

Current that will trigger all devices

$V_D = 12 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$   $I_{GT} > 500 \text{ mA}$

Minimum reverse breakdown voltage

$I_{GR} = 1.0 \text{ mA}$   $V_{(BR)GR} > 10 \text{ V}$

**Switching characteristics (resistive load)**

Turn-on when switched to  $I_T = 10 \text{ A}$  from  $V_D = 250 \text{ V}$

with  $I_{GF} = 2.5 \text{ A}; T_j = 25 \text{ }^\circ\text{C}$

delay time

$t_d < 0.3 \text{ } \mu\text{s}$

rise time

$t_r < 1.5 \text{ } \mu\text{s}$

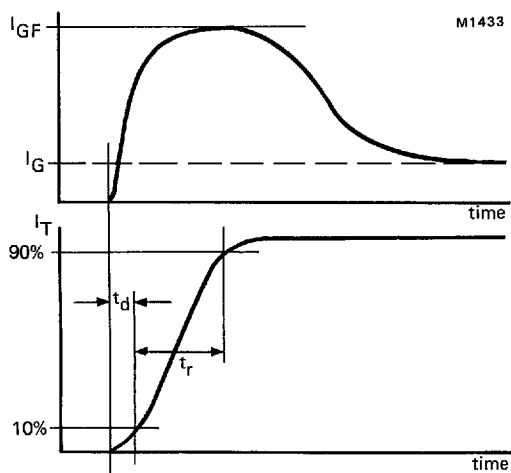


Fig.2 Waveforms.

\*Measured under pulse conditions to avoid excessive dissipation.

\*\*Below latching level the device behaves like a transistor with a gain dependent on current.

**Switching characteristics (inductive load)**

Turn-off when switched from  $I_T = 10\text{ A}$  to  $V_D = V_{Dmax}$ :

$V_{GR} = 10\text{ V}$ ;  $L_G \leq 0.5\ \mu\text{H}$ ;  $L_S \leq 0.25\ \mu\text{H}$ ;  $C_S \geq 20\text{ nF}$ ;  $T_j = 85\text{ }^\circ\text{C}$

storage time	$t_s$	<	0.60	$\mu\text{s}$
fall time	$t_f$	<	0.25	$\mu\text{s}$
peak reverse gate current	$I_{GR}$	<	10	A

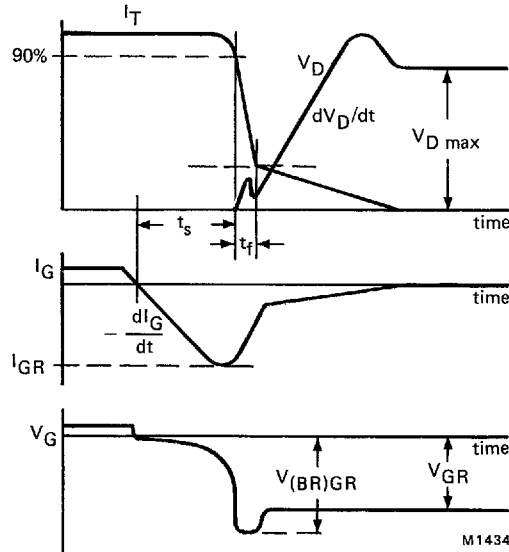


Fig.3 Waveforms.

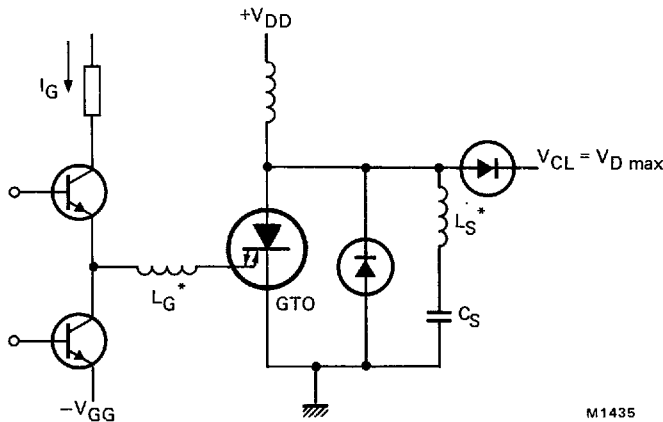


Fig.4 Inductive load test circuit.

\*Indicates stray series inductance only.

Switching characteristics (circuit-commutated)\*

Turn-off time

$I_T = 50 \text{ A}$ ;  $-di_T/dt = 10 \text{ A}/\mu\text{s}$ ;  $dV_D/dt = 200 \text{ V}/\mu\text{s}$ ;

$V_{GR} = 5 \text{ V}$ ;  $T_j = 120 \text{ }^\circ\text{C}$

$t_q < 1.0 \mu\text{s}$

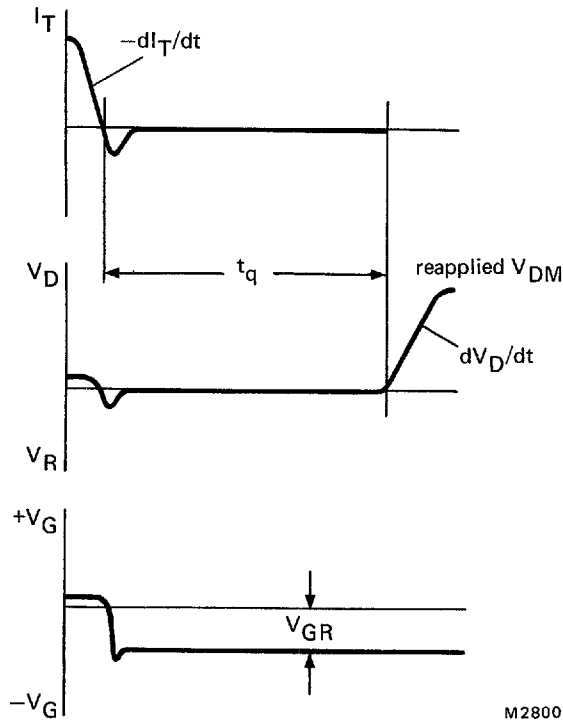


Fig.5 Circuit-commutated turn-off time definition.

\*Figs. 7, 11, 12, 13, 15, 16, 17 do not apply to commutated turn-off.

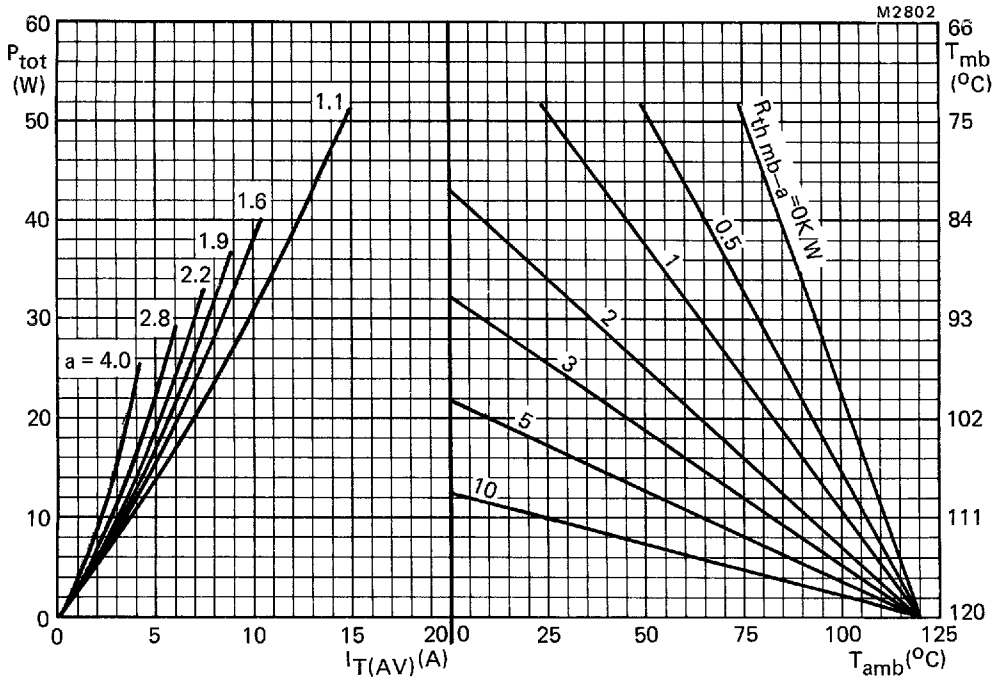


Fig.6 The right hand part shows the interrelationship between the power (derived from the left-hand part) and the maximum permissible temperatures.

$$a = \text{form factor} = \frac{I_T(\text{RMS})}{I_T(\text{AV})}$$

P = power excluding switching losses.

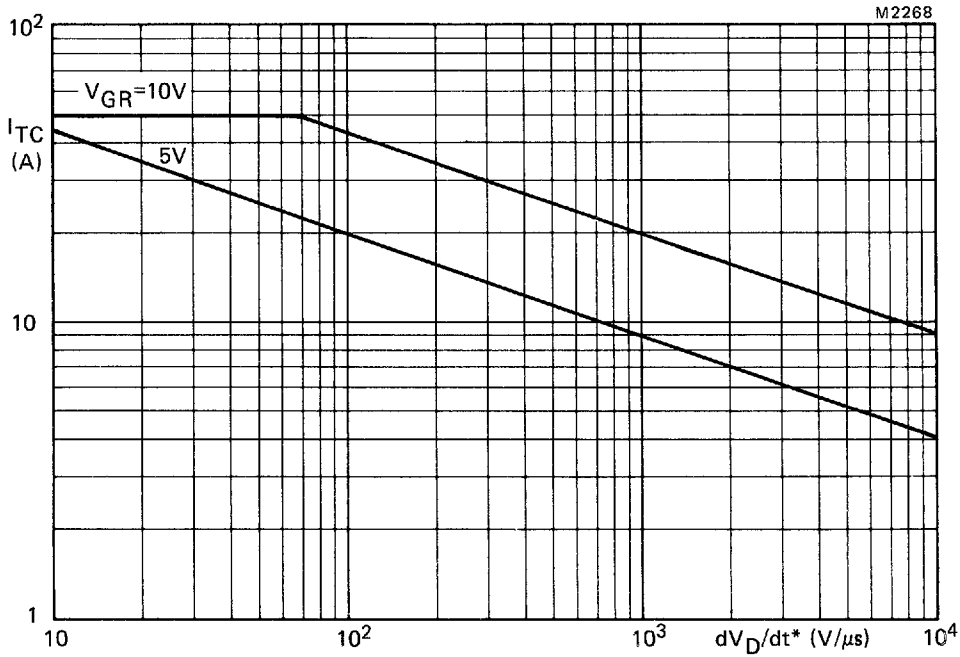


Fig.7 Anode current which can be turned off versus applied  $dV_D/dt^*$ ; inductive load;  
 $L_G \leq 0.5 \mu H$ ;  $L_S \leq 0.25 \mu H$ ;  $T_j = 120 \text{ }^\circ\text{C}$ .

\* $dV_D/dt$  is calculated from  $I_T/C_S$ .

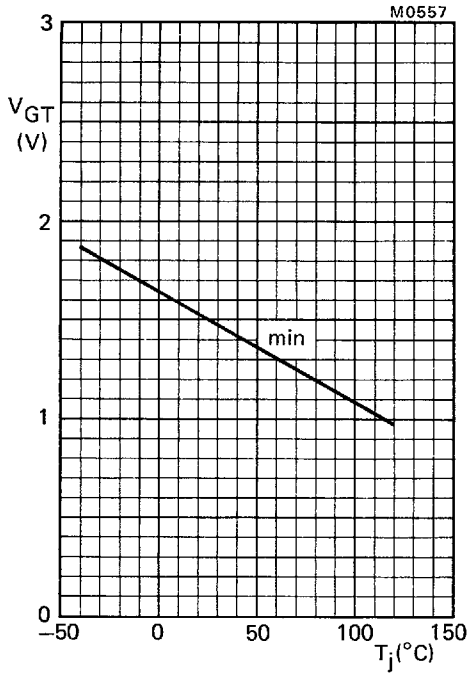


Fig.8 Minimum gate voltage that will trigger all devices as a function of junction temperature;  $V_D = 12$  V.

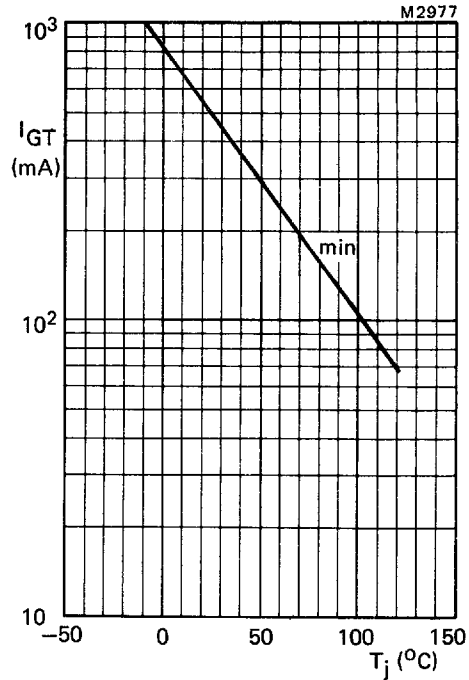


Fig.9 Minimum gate current that will trigger all devices as a function of junction temperature;  $V_D = 12$  V.

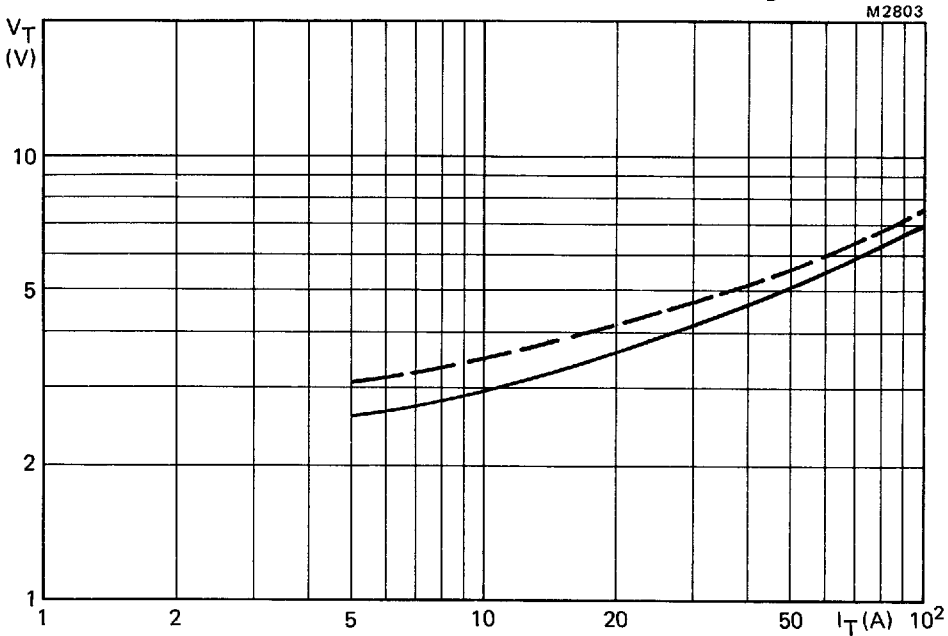


Fig.10 Maximum  $V_T$  versus  $I_T$ ; ---  $T_j = 25$  °C; —  $T_j = 120$  °C;  $I_G = 0.5$  A.

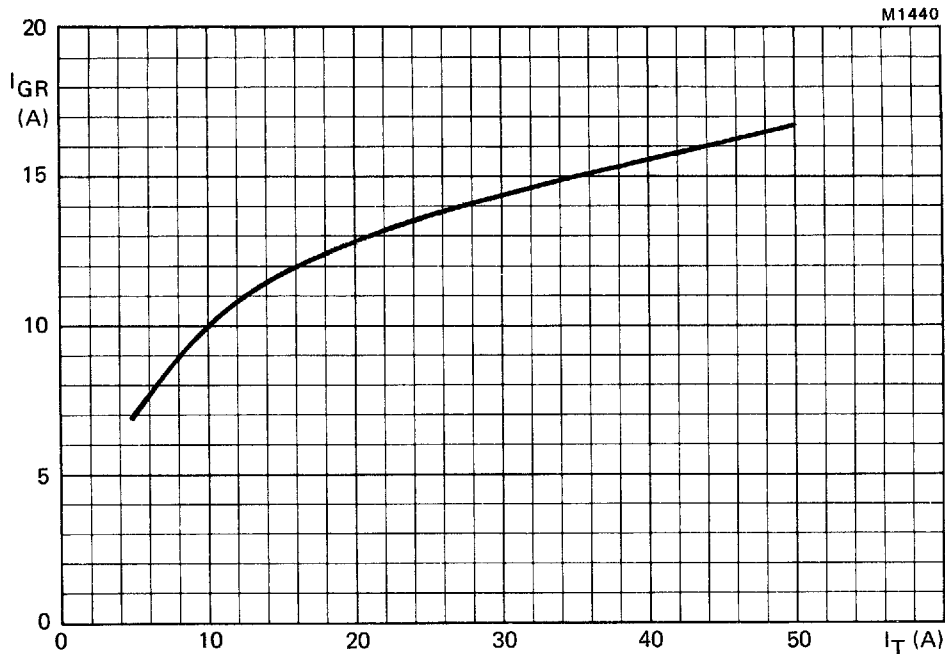


Fig.11 Peak reverse gate current versus anode current at turn-off; inductive load;  
 $V_{GR} = 10$  V;  $I_G = 0.5$  A;  $L_G = 0.4$   $\mu$ H;  $T_j = 120$   $^{\circ}$ C; maximum values.

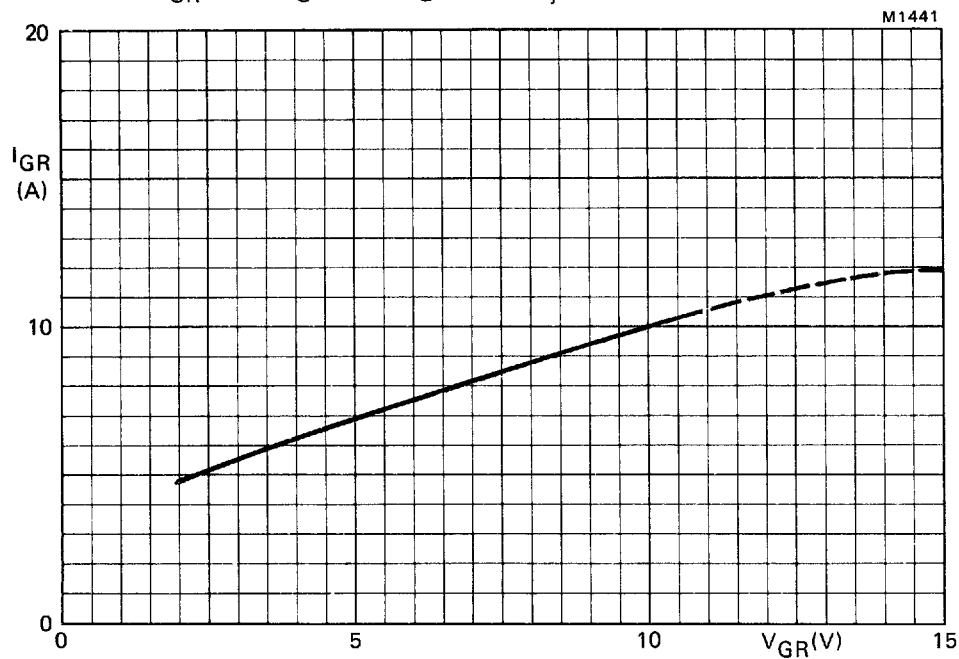


Fig.12 Peak reverse gate current versus applied reverse gate voltage; inductive load;  
 $I_T = 10$  A;  $I_G = 0.5$  A;  $L_G = 0.4$   $\mu$ H;  $T_j = 120$   $^{\circ}$ C; maximum values.

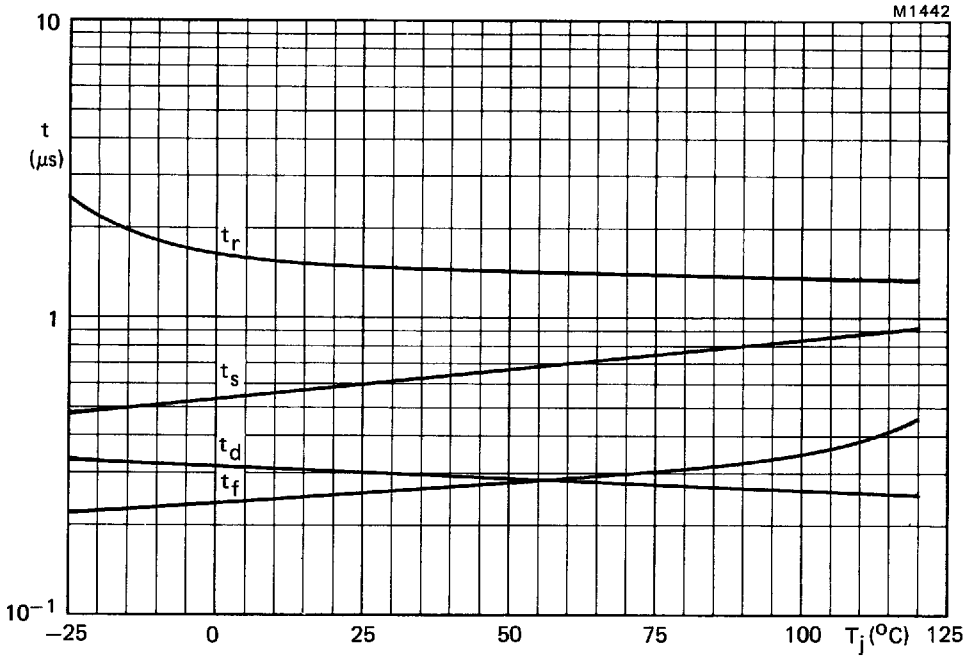


Fig.13 Switching times as a function of junction temperature;  $V_D \geq 250 \text{ V}$ ;  $I_T = 10 \text{ A}$ ;  $I_{GF} = 1.0 \text{ A}$ ;  $V_{GR} = 10 \text{ V}$ ;  $I_G = 0.5 \text{ A}$ ;  $L_G = 0.4 \mu\text{H}$ ; maximum values.

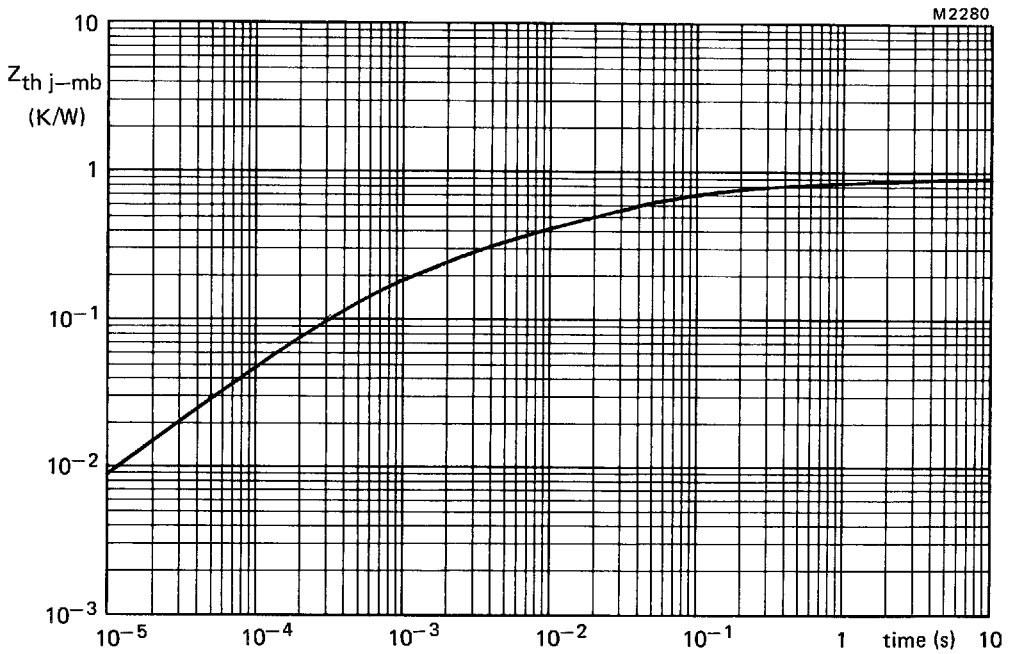


Fig.14 Transient thermal impedance.

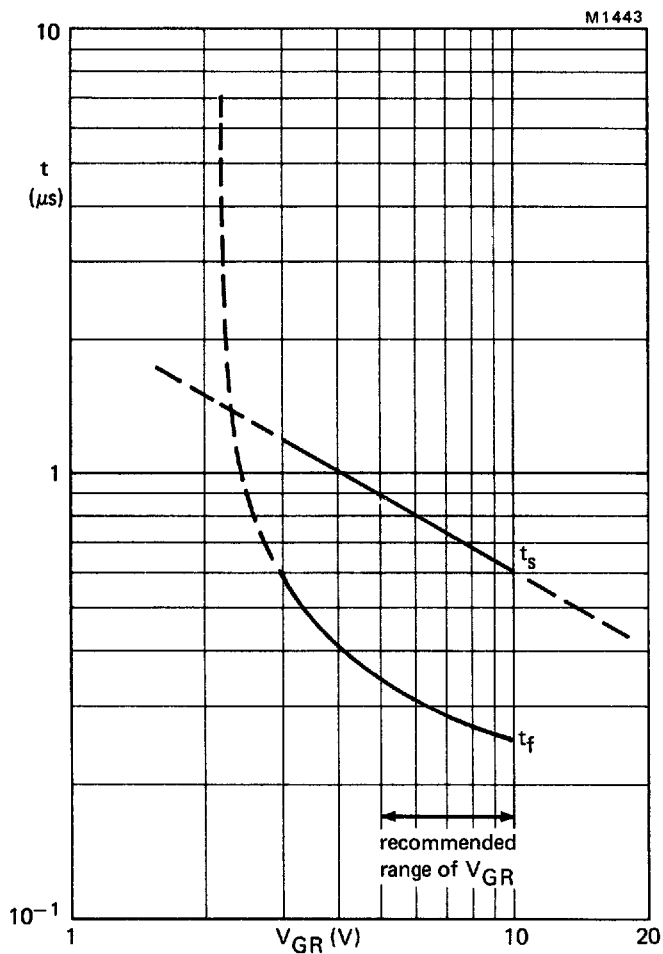


Fig.15 Storage and fall times versus applied reverse gate voltage; inductive load,  $I_T = 10$  A;  $I_G = 0.5$  A;  $L_G = 0.4 \mu H$ ;  $T_j = 25^\circ C$ ; maximum values.

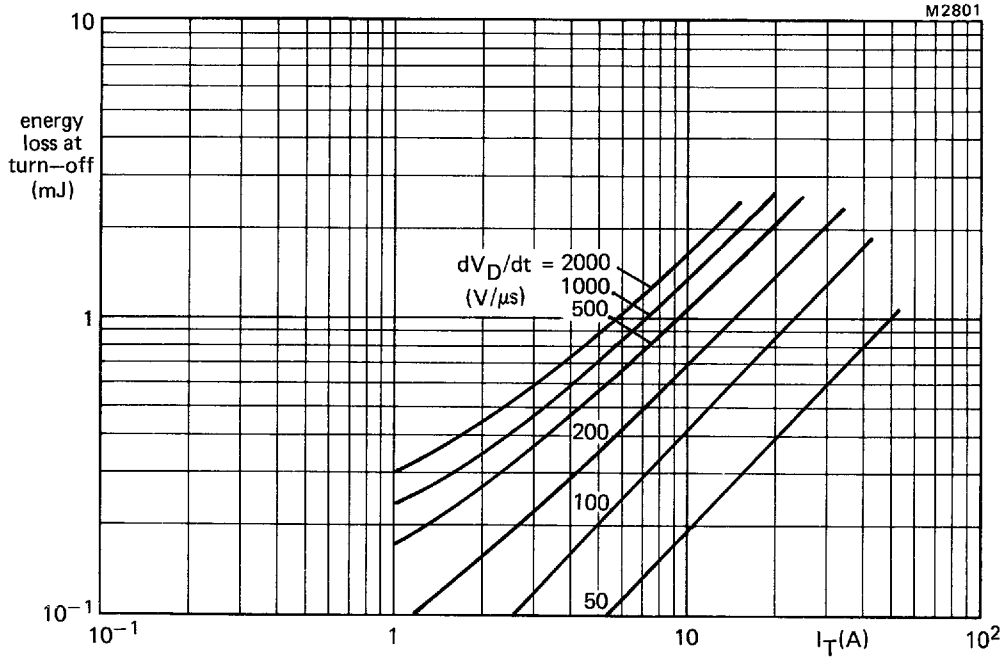


Fig.16 Maximum energy loss at turn-off (per cycle) as a function of anode current and applied  $dV_D/dt$  (calculated from  $I_T/C_S$ );  $dV_D/dt$  linear up to  $V_D = V_{DWmax}$ ;  $V_{GR} = 10 V$ ;  $I_G = 0.5 A$ ;  $L_G < 0.5 \mu H$ ;  $L_S < 0.25 \mu H$ ;  $T_j = 120 ^\circ C$ .

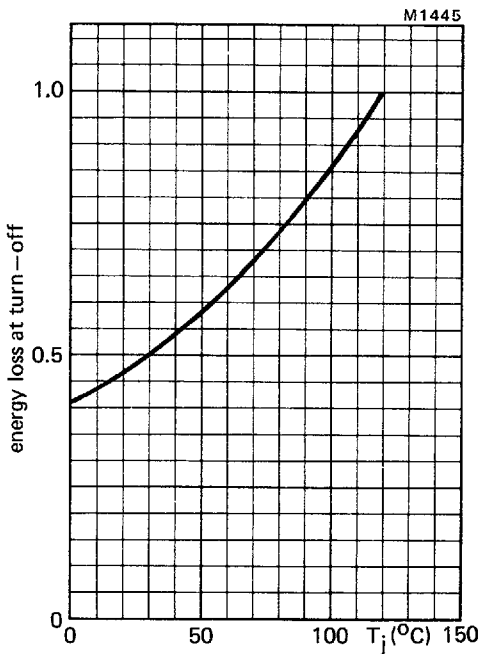


Fig.17 Energy loss at turn-off as a function of junction temperature;  $I_G = 0.5 A$ ;  $V_{GR} = 10 V$ . Normalised to  $T_j = 120 ^\circ C$ .

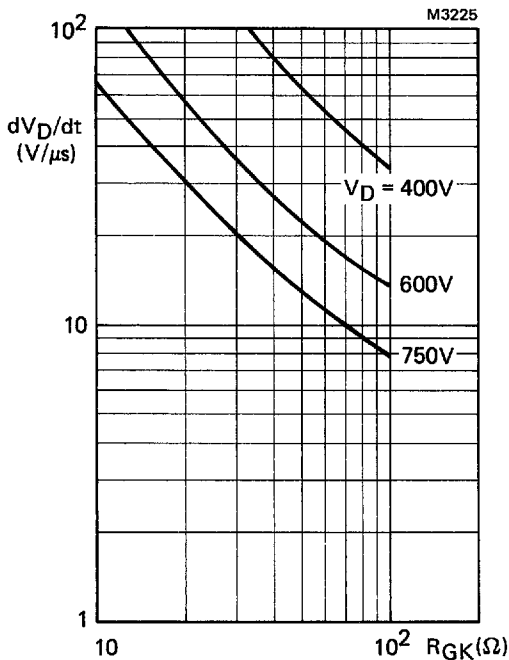


Fig.18 Linear rate of rise of off-state voltage versus gate-cathode resistance;  $T_j = 25^\circ C$ ; typical values.

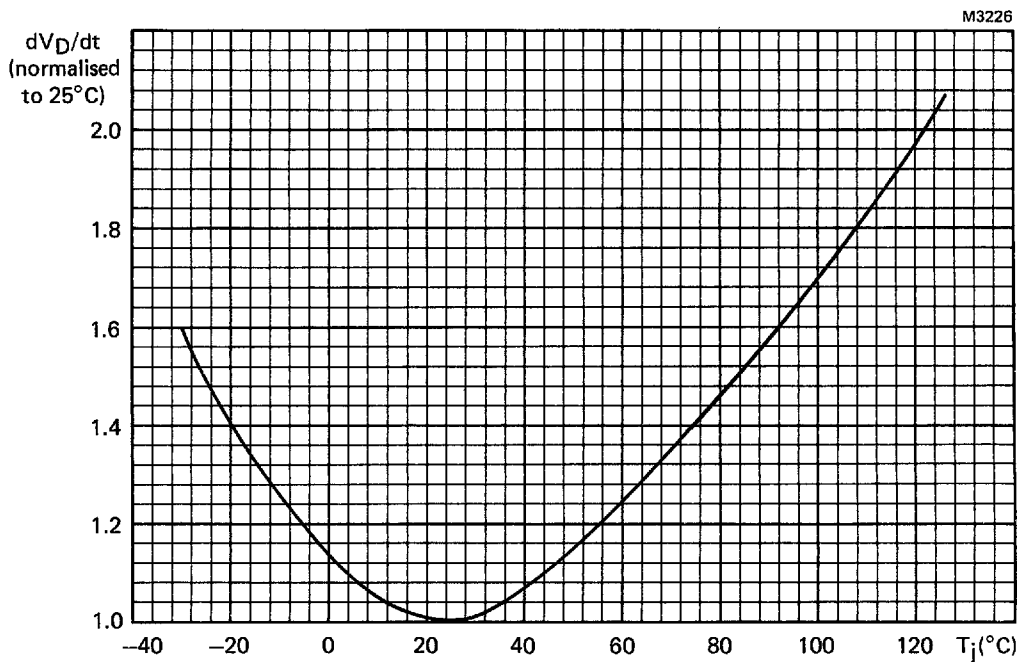


Fig.19 Rate of rise of off-state voltage versus junction temperature, normalised to 25°C;  $V_{Dmax} = 750V$ ;  $R_{GK} = 22 \Omega$ ; typical values.